

Title (en)

METHOD FOR DETERMINING A PRODUCTION PARAMETER FOR A RESISTIVE RANDOM-ACCESS MEMORY CELL

Title (de)

VERFAHREN ZUR BESTIMMUNG EINES PRODUKTIONSPARAMETERS FÜR EINE RESISTIVE DIREKTZUGRIFFSPEICHERZELLE

Title (fr)

PROCÉDÉ DE DÉTERMINATION D'UN PARAMÈTRE DE FABRICATION D'UNE CELLULE DE MÉMOIRE VIVE RÉSISTIVE

Publication

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Application

**EP 20731866 A 20200611**

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Abstract (en)

[origin: WO2020249697A1] The invention relates to a method for determining at least one value ( $t_{TE\_opt}$ ,  $t_{OX\_opt}$ ,  $X_{opt}$ ) of at least one production parameter ( $t_{TE}$ ,  $t_{OX}$ ,  $x$ ) for a resistive memory cell, the resistive memory cell comprising a thin-film stack, said method comprising the following steps: - providing (S1) a plurality of reference memory cells (10) corresponding to a plurality of technological variants of the thin-film stack; - measuring (S2) an initial resistance value ( $R_i$ ) for each reference memory cell; - determining (S3, S4), for each reference memory cell (10), a value of a programming parameter chosen from among the resistance in a high-resistance state (RHRS) and the programming window; - establishing (S5) a relationship between the programming parameter and the initial resistance ( $R_i$ ) based on the initial resistance values ( $R_i$ ) and the values of the programming parameter; and - determining said at least one value ( $t_{TE\_opt}$ ,  $t_{OX\_opt}$ ,  $X_{opt}$ ) of said at least one production parameter ( $t_{TE}$ ,  $t_{OX}$ ,  $x$ ) for which the programming parameter is greater than or equal to a target value (RHRS<sub>tg</sub>), based on said relationship between the programming parameter and the initial resistance ( $R_i$ ) and on at least one dependency relationship between the initial resistance ( $R_i$ ) and said at least one production parameter ( $t_{TE}$ ,  $t_{OX}$ ,  $x$ ).

IPC 8 full level

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